

**Notice of References Cited**

Application/Control No.

09/838,743

Applicant(s)/Patent Under  
Reexamination  
DEBOY ET AL.

Examiner

Johannes P Mondt

Art Unit

2826

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,702,961	12-1997	Park	437/40
	C	US-6,011,280	01-2000	Fruth et al.	257/137
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	N	JP404234173A	08-1992	Japan	Yamamoto	H01L029/784
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Laska et al, "A 2000 V-Non-Punch-Through-IGBT with Dynamical Properties like a 1000 V-IGBT", Int. Electron Dev. Mtg., New York, IEEE, 1990 (pages 807-810) (IDS, hence not provided herewith)
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.